

ABSTRACT OF THE DISCLOSURE

[0081] A fixture assembly (100, 102) is presented. The fixture assembly includes a device interface assembly (102) for mating with a device under test and a tester interface assembly (100) for mating with the device interface assembly (102) on one side and a tester on a second side. In the method and apparatus of the present invention, the device interface assembly (102) includes a probe field specific to a device under test and may be changed to accommodate a different device, without changing the tester interface assembly. The tester interface assembly (100) includes a custom electronic module (400) and a standardized electronic module (410), which are both coupled to a PCB interface (300) in the tester interface assembly (100). As such, both standardized and specialized test may be modified and changed without redesigning the tester interface assembly (100).